

NanoSIMS 50: Optics and practical aspects of Tuning

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Cameca France

1/ Primary column and secondary transfer optic.

- Chromatic compensation: L3
- Probe size
- Cross over and Images positions.
- Dynamic transfer and EOS.
- Practical rules for EOS tuning

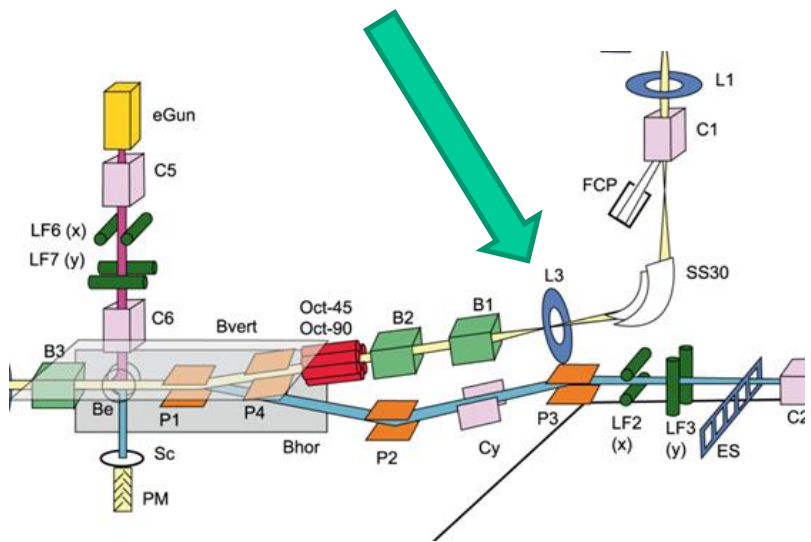
2/ Mass spectrometer and Mass Resolving Power.

- Mass spectrometer: how it works?
- MRP and aberrations
- Shaping optics
- Second order aperture aberrations
- Practical rules for MRP tuning

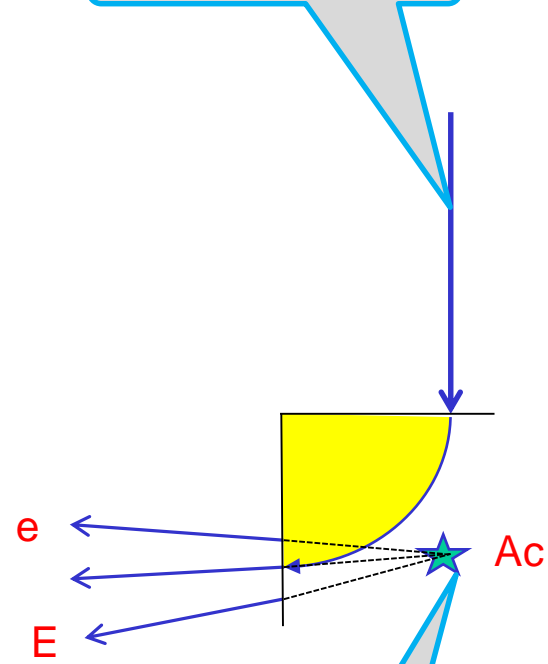
3/ New O^- ion source

- How it works?
- Preliminary performances

Chromatic compensation: L3

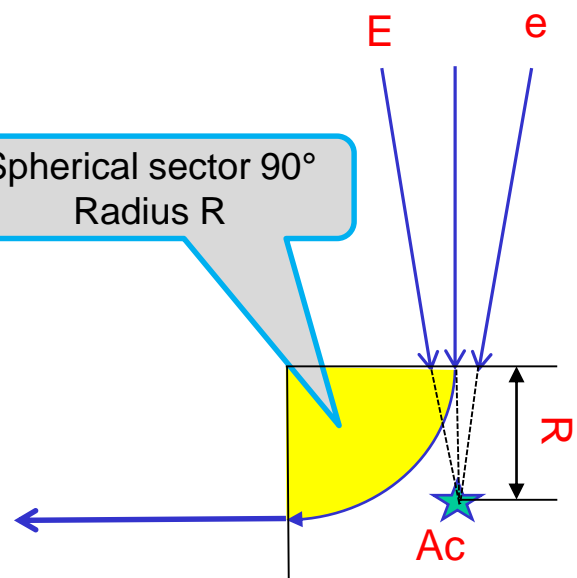


Chromatic beam



Achromatic point

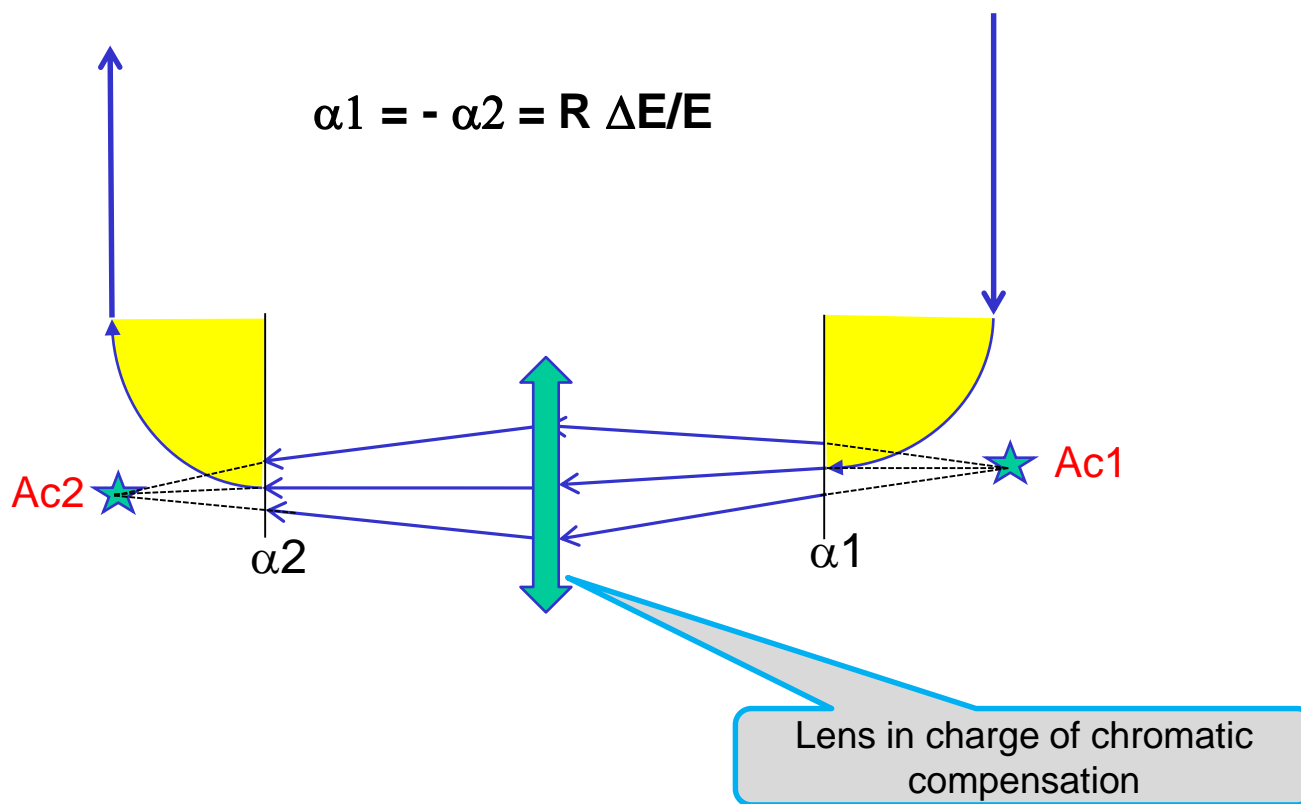
Spherical sector 90°
Radius R



$$\alpha = R \Delta E/E$$

Chromatic compensation: L3

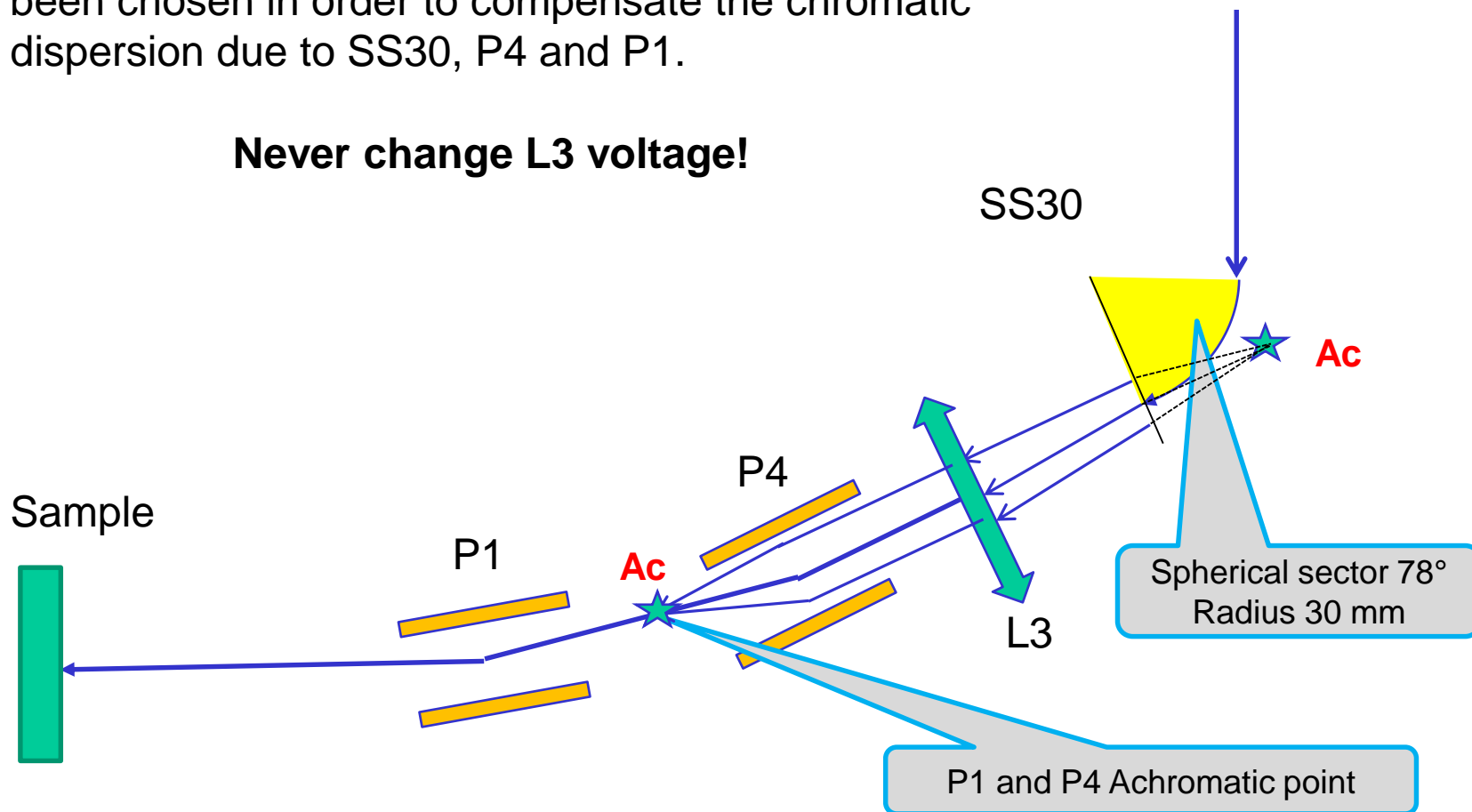
- Two spherical electrostatic sectors, radius = R
- Chromatic compensation of a polychromatic beam.
- Ac2 is the image of Ac1.



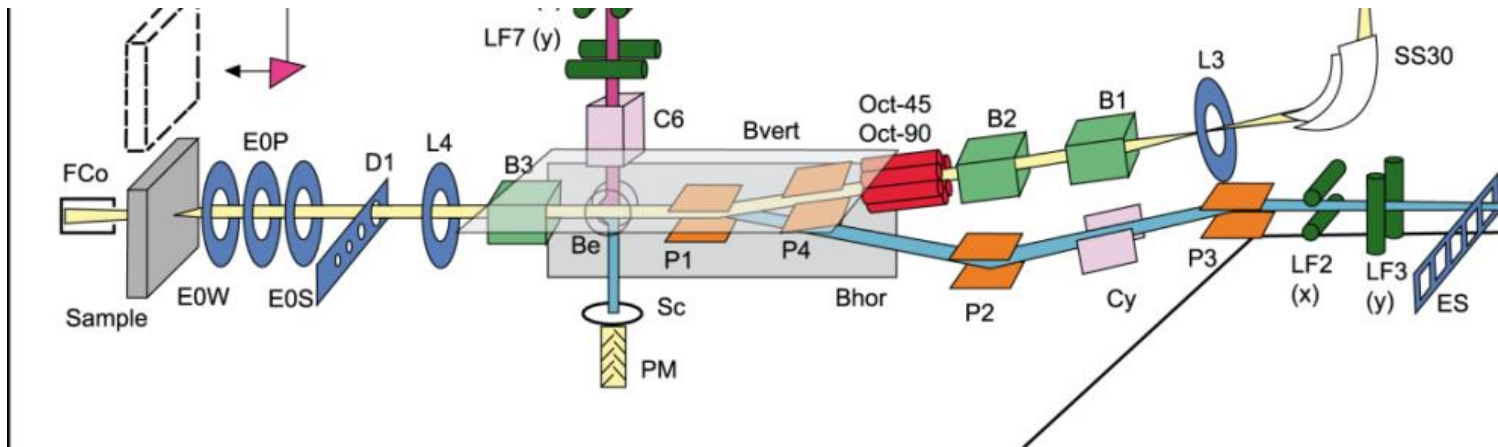
Chromatic compensation: L3

L3 position and voltage (6043 Volts @ 8 keV) have been chosen in order to compensate the chromatic dispersion due to SS30, P4 and P1.

Never change L3 voltage!



Secondary optics and dynamic transfer

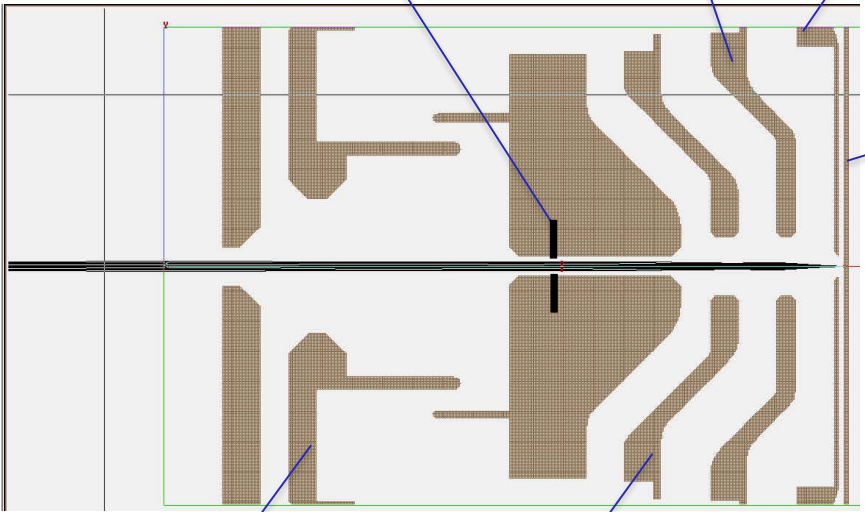


- P1, P2, P3, P4: Static plates. Value of angular deviation defined only by space considerations. 6° for P1, P3, P4 and 12° for P2.
- B1, B2, B3: scanning plates, 2 functions:
 - Scanning the primary ion beam on the sample
 - Maintaining the collection efficiency and the mass resolving power while the primary ion beam is scanned on the sample.

N50L Lateral Resolution

Immersion lens E0

D1 E0P / 8,5 kV E0W / - 8 kV



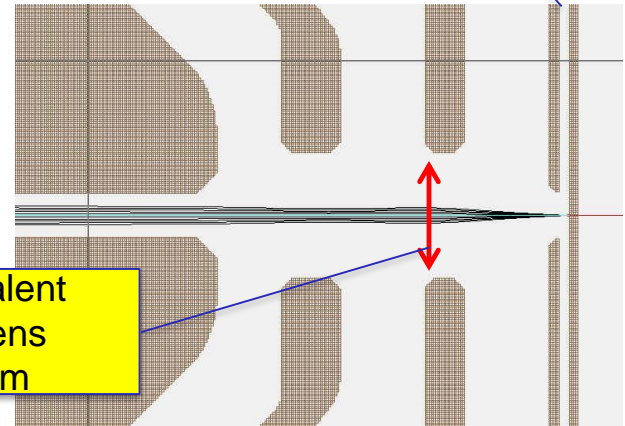
Sample / - 8 kV

L4 / - 7,1 kV

E0S / - 7,1 kV

Cs+ mode

E0W-Sample distance 400 μm



E0P equivalent to a thin lens
 $f = 6,5 \text{ mm}$

N50L Lateral Resolution Aberrations and Brightness

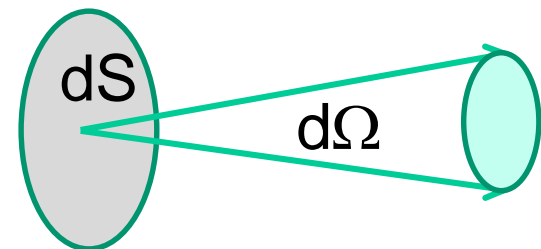
Probe size = Σ (gaussian part + aberrations)

Main aberrations :

- Aperture aberration : $C_s \alpha^3$
- Chromatic aberration : $C_c \alpha \Delta E/E$
- α being the primary ion beam aperture at the sample and $\Delta E/E$
- the relative energy dispersion.
- Aberration coefficients C_s and C_c are linked to the optical properties of the immersion lens. Respective values are 62 mm and 15 mm.
- Gaussian part is linked to the **Brightness**

$$I(A) = B \, dS_{(cm^2)} \, d\Omega_{(sr)}$$

B : $A \, m^{-2} \, sr^{-1} \, V^{-1}$ or $A \, cm^{-2} \, sr^{-1} \, @ \, 10 \, kV$



N50L Lateral Resolution Probe size estimation

$$D_p = \sqrt{(D_{Br}^{1,3} + D_s^{1,3})^{2/1,3} + D_c^2}$$

With:

- $D_c = 0,6 Cc \alpha_s \Delta E/E$ Chromatic
- $D_s = 0,18 Cs \alpha_s^3$ Aperture
- $D_{Br} = (Ip/B\alpha_s^2 4/\pi^2)^{1/2}$ Brightness
- $D_p = FWHM \longrightarrow D68 (+30\%)$

[1] J. E. Barth and P. Kruit, Optik, n°3 (1996) 101-109

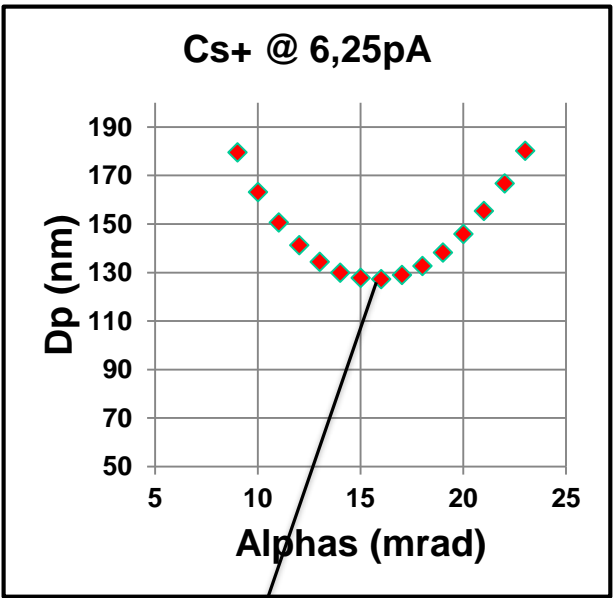
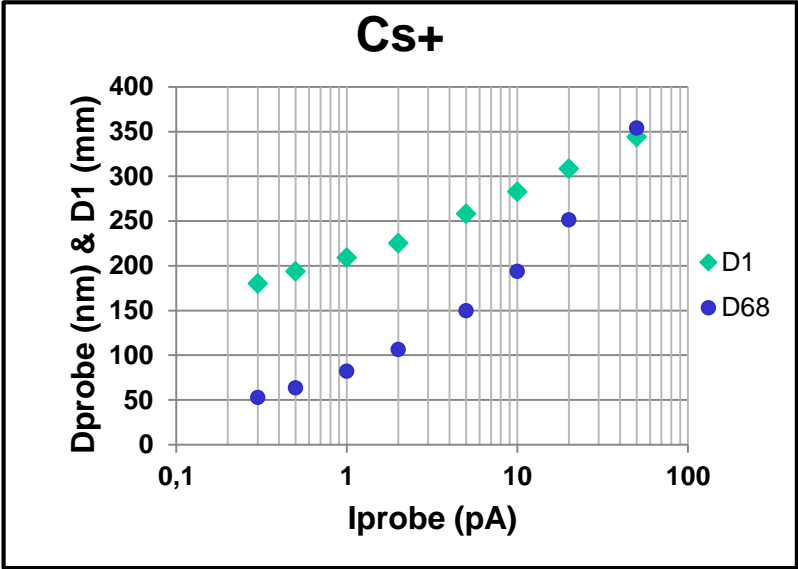
[2] M. S. Bronsgeest, J. E. Barth, L.W. Swanson and P. Kruit, J. Vac. Sci. Technol. B 26(3) May/June 2008, 949-955

N50L Lateral Resolution Probe size estimation

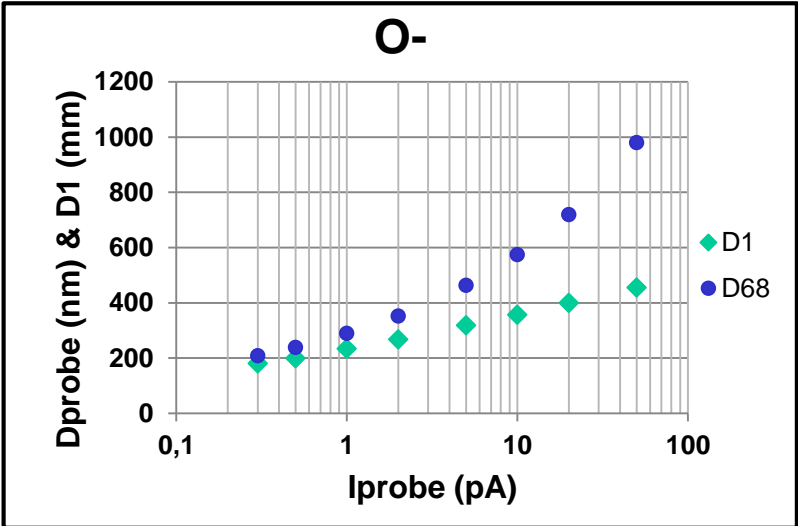
$$D_p = \sqrt{(D_{Br}^{1,3} + D_s^{1,3})^{2/1,3} + D_c^2}$$

For each set of parameters one can find one α_s which minimizes D_p .

Cs+ : 100 A cm⁻² sr⁻¹ – 1eV
O- : 10 A cm⁻² sr⁻¹ – 15eV



D1 = 265 μm



N50L Lateral Resolution Future developments

How could we increase the lateral resolution?

1/ Acting on the source by increasing the brightness and decreasing the energy dispersion.

2/ Acting on the immersion lens by decreasing aberrations coefficients

N50L Lateral Resolution Future developments

Acting on the source by increasing the brightness and decreasing the energy dispersion.

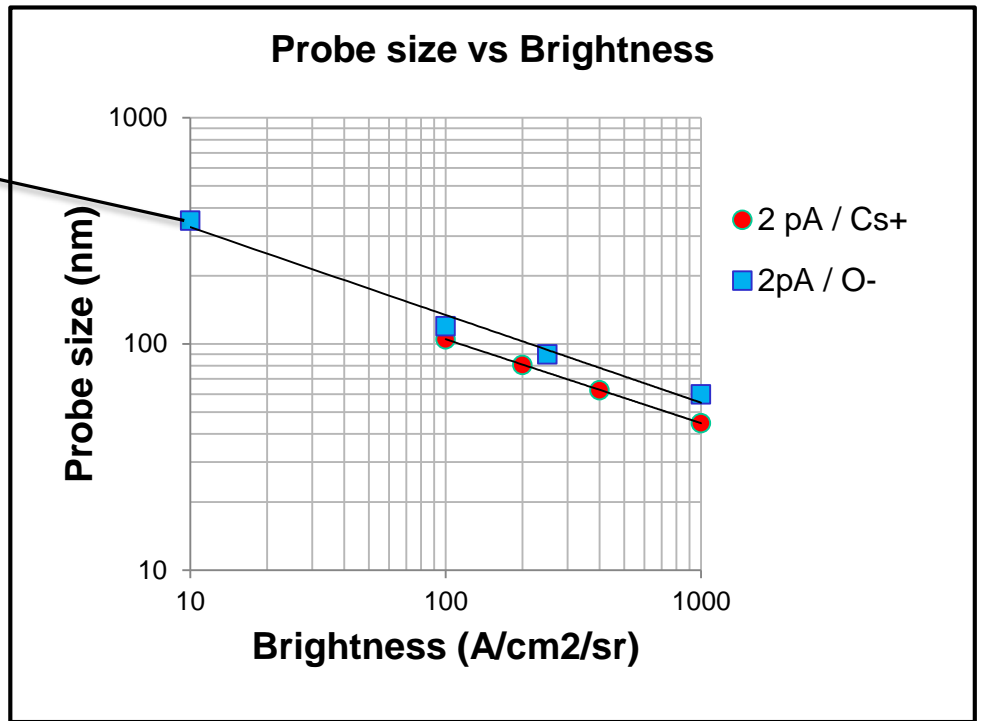
$\Delta E/E = 15/8000$ (Duo source)

Cs = 63 mm and Cc = 16 mm

Cs+ : $\Delta E/E = 1/8000$

O- : $\Delta E/E = 5/8000$ (RF source)

$$D_p \propto B^{-0,39}$$

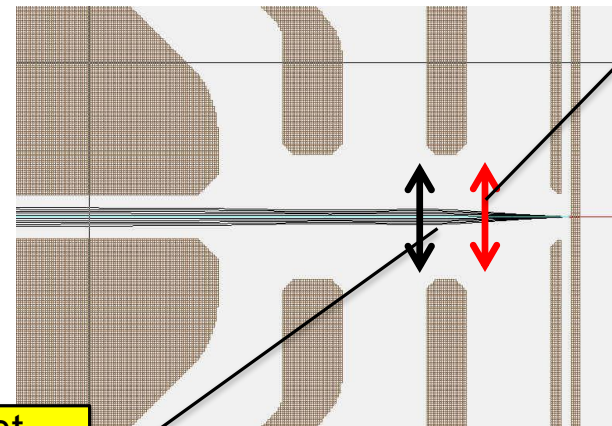


N50L Lateral Resolution Future developments

Acting on the immersion lens by decreasing aberrations coefficients?

C_s and C_c are proportional to f^n , decreasing f will decrease C_c and C_s

- C_s : 63 mm to 27 mm
- C_c : 16 mm to 11 mm



f = 4 mm

EOP equivalent
to a thin lens
f = 6.5 mm

1 pA – 82 nm to **1 pA – 66 nm** for $B = 100 \text{ A cm}^{-2} \text{ sr}^{-1}$

1/ Primary column and secondary transfer optic.

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- Probe size
- Cross over and Images positions.
- Dynamic transfer and E0S.
- Practical rules for E0S tuning

2/ Mass spectrometer and Mass Resolving Power.

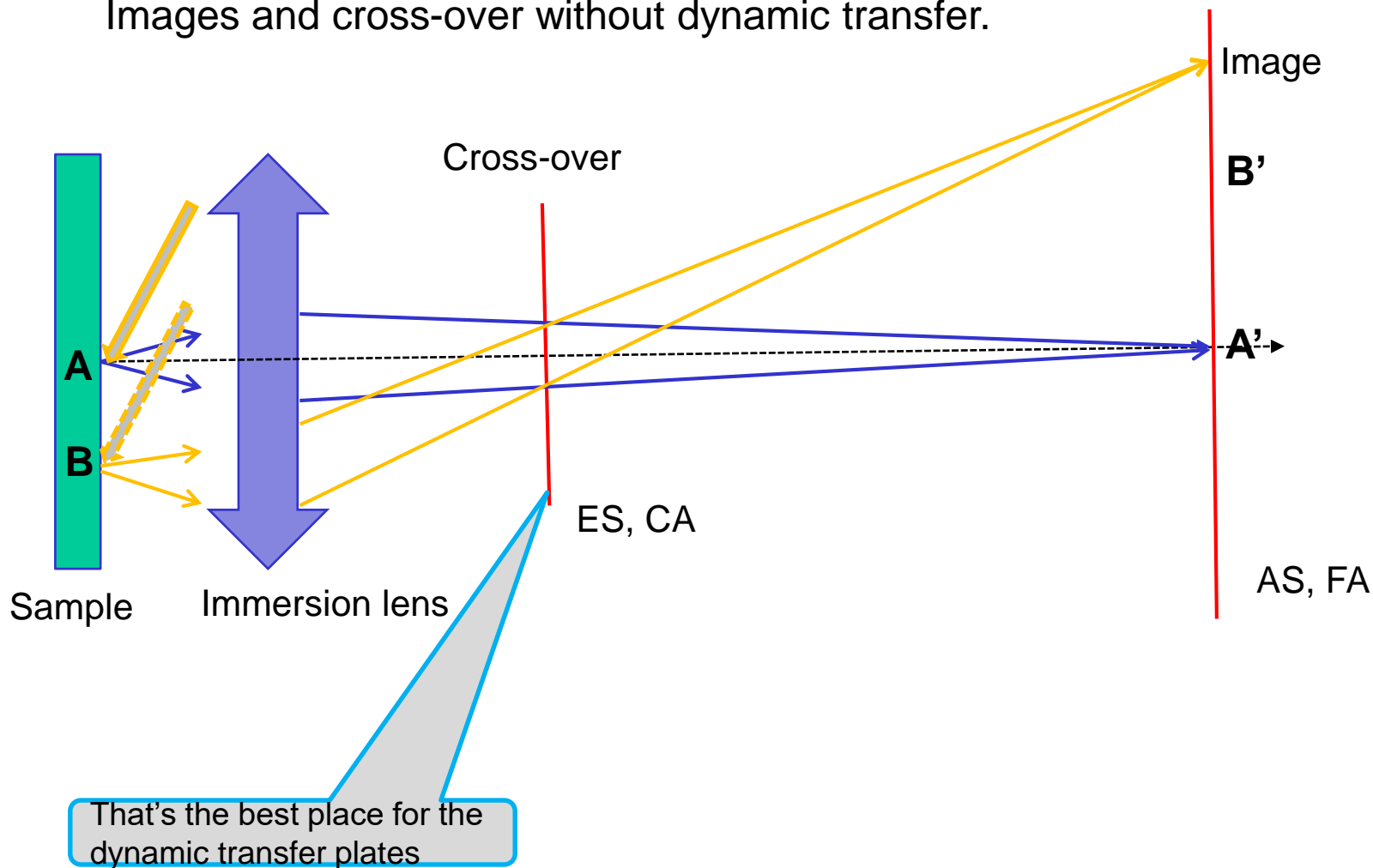
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3/ New O^- ion source

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- Preliminary performances

Secondary optics and dynamic transfer

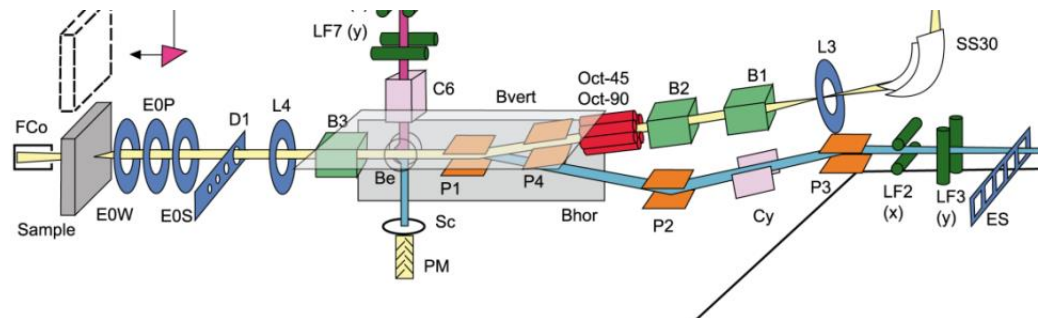
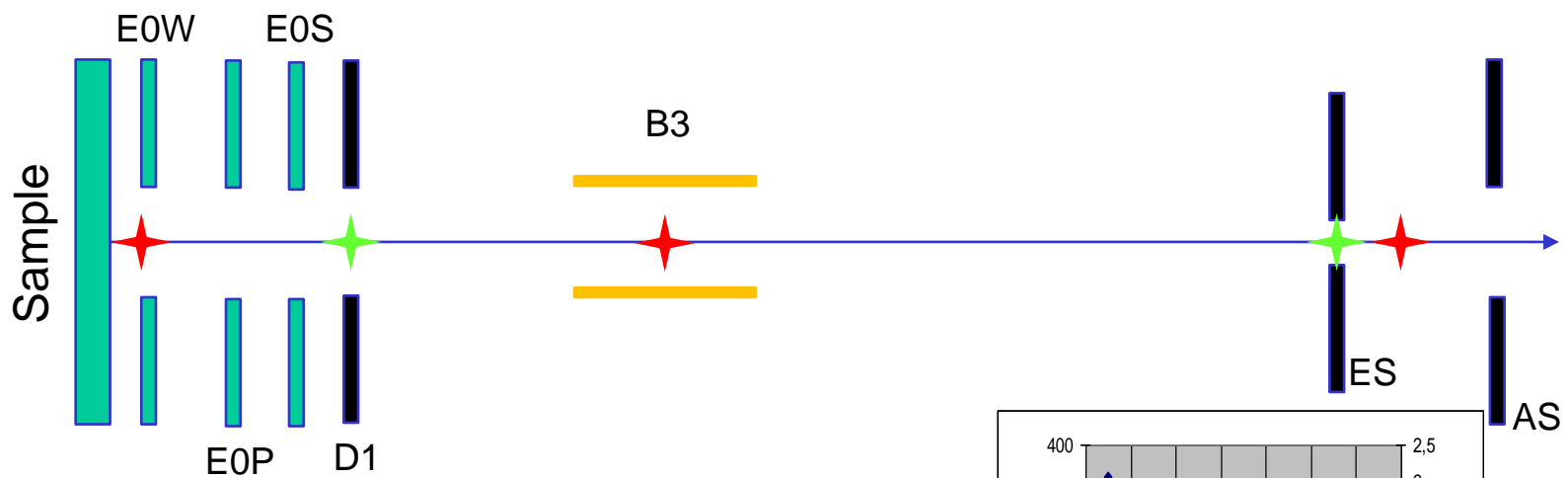
Classical optical schematic IMS XF and IMS1280.
Images and cross-over without dynamic transfer.



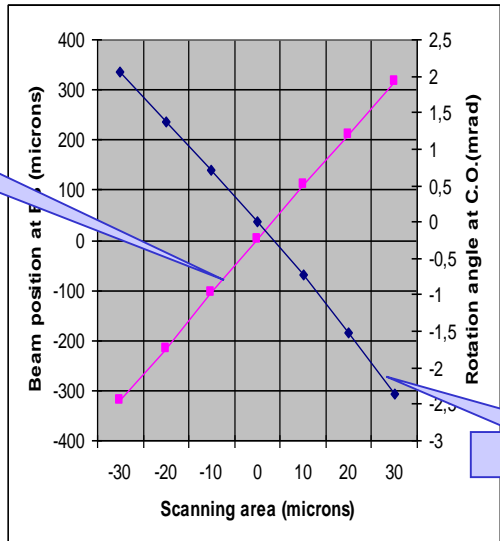
Secondary optics and dynamic transfer

NanoSIMS 50 optical schematic (horizontal plane)

Images  and cross-over  positions.



Angle at C.O.

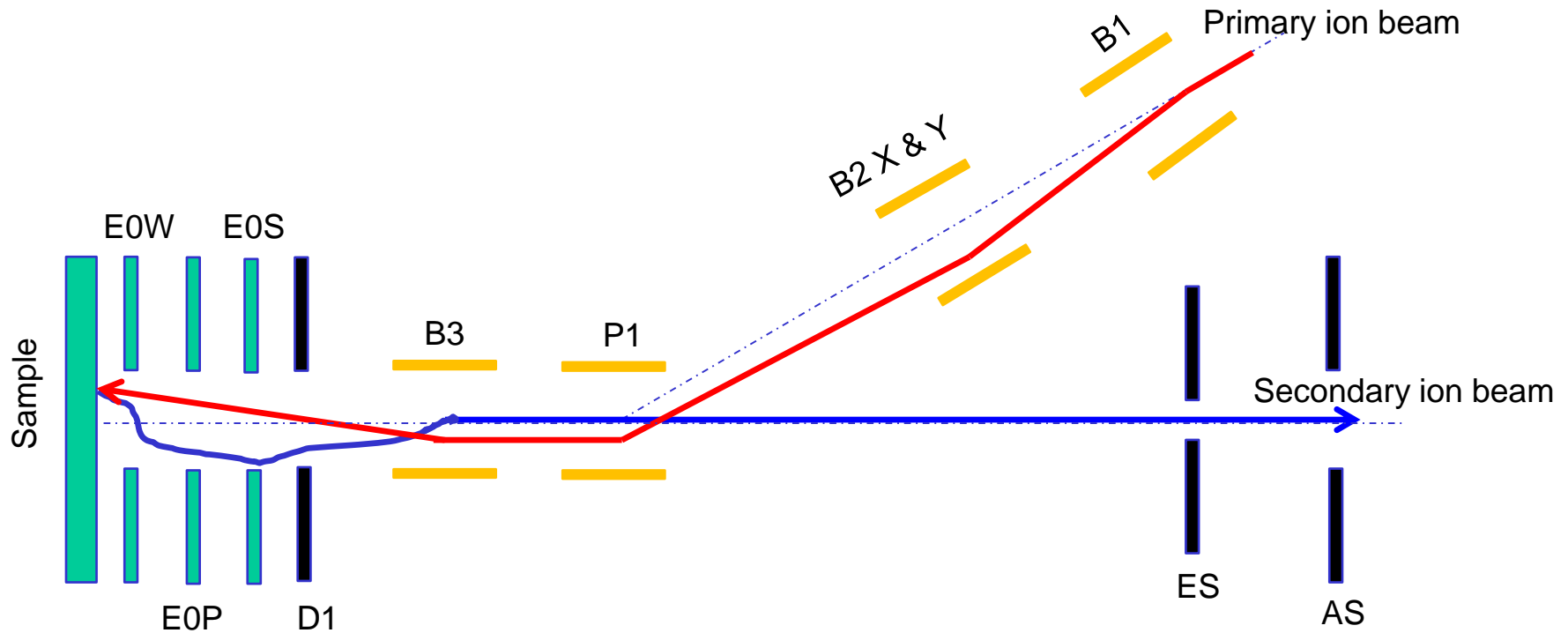


Position at ES

Secondary optics and dynamic transfer

How does it work?

- B1, B2 and B3 rotate the primary ion beam around the center of D1.
- B3 in addition to its action on the primary ion beam is in charge of the “Dynamic transfer”. B3 is powered so as to cancel the secondary ion beam motion
- B2X and B2Y could be set to different values to take in account the difference between the horizontal and vertical planes



Secondary optics and dynamic transfer

While the sample is moving in Z, EOS has to be modified to keep the beam waist position at ES plane, leading to a slight movement of the C.O. in B3.

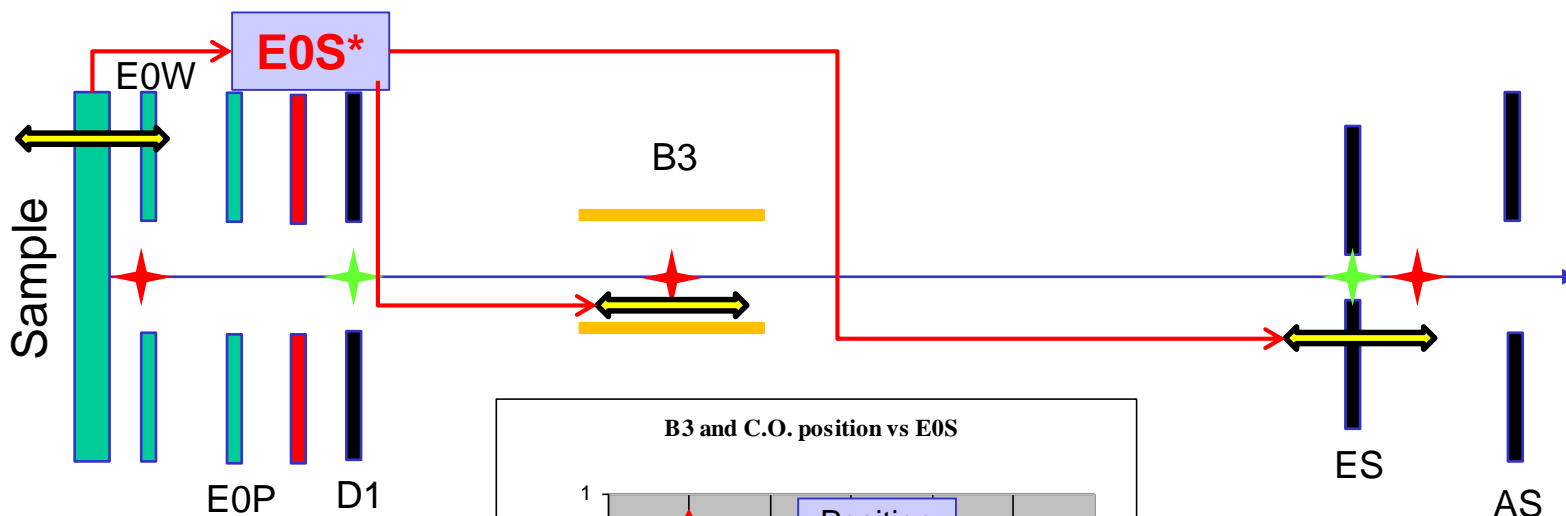
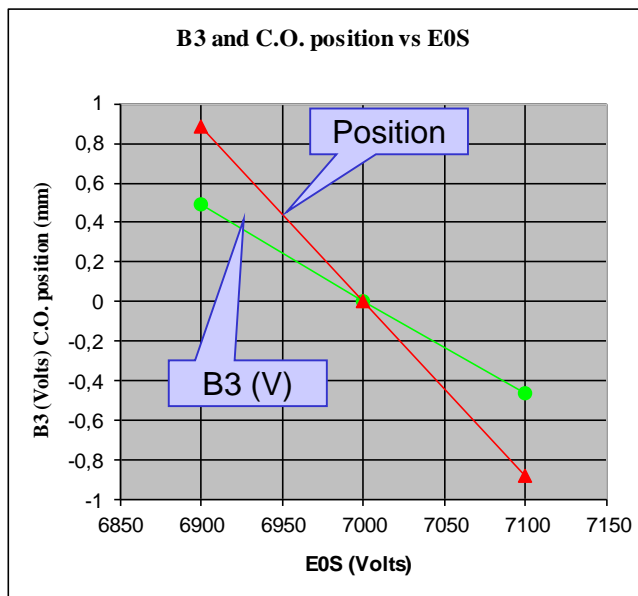


Image cross-over



Simulation conditions :

- B3 = 10 Volts
- Sec. Ions emitted at 30 microns.
- EOS reference : 7000 Volts

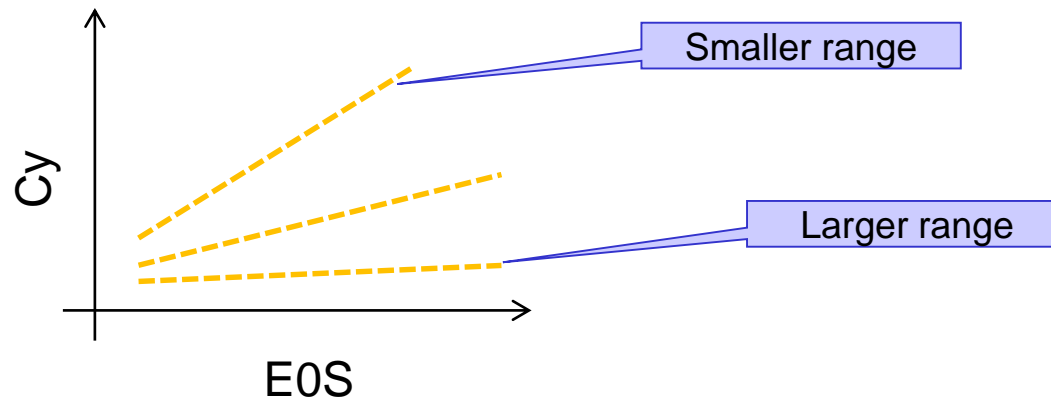
Secondary optics and dynamic transfer

Practical rules for E0S:

Keep E0S as constant as possible!

- Elemental imaging without isotopic ratios measurements:
E0S* +/- 30 bits. (1 bit is 1,5 micron and 2,5 Volts)
- Low reproducibility Isotopic ratios measurements (by imaging or not) (Sigma > 2-3 permil) : **E0S* +/- 20 bits.**
- High reproducibility Isotopic ratios measurements (by imaging or not) (Sigma < 1 permil) : **E0S* +/- 10 bits.**

These ranges of value for E0S are varying from instrument to instrument depending of the relationship between E0S and Cy.



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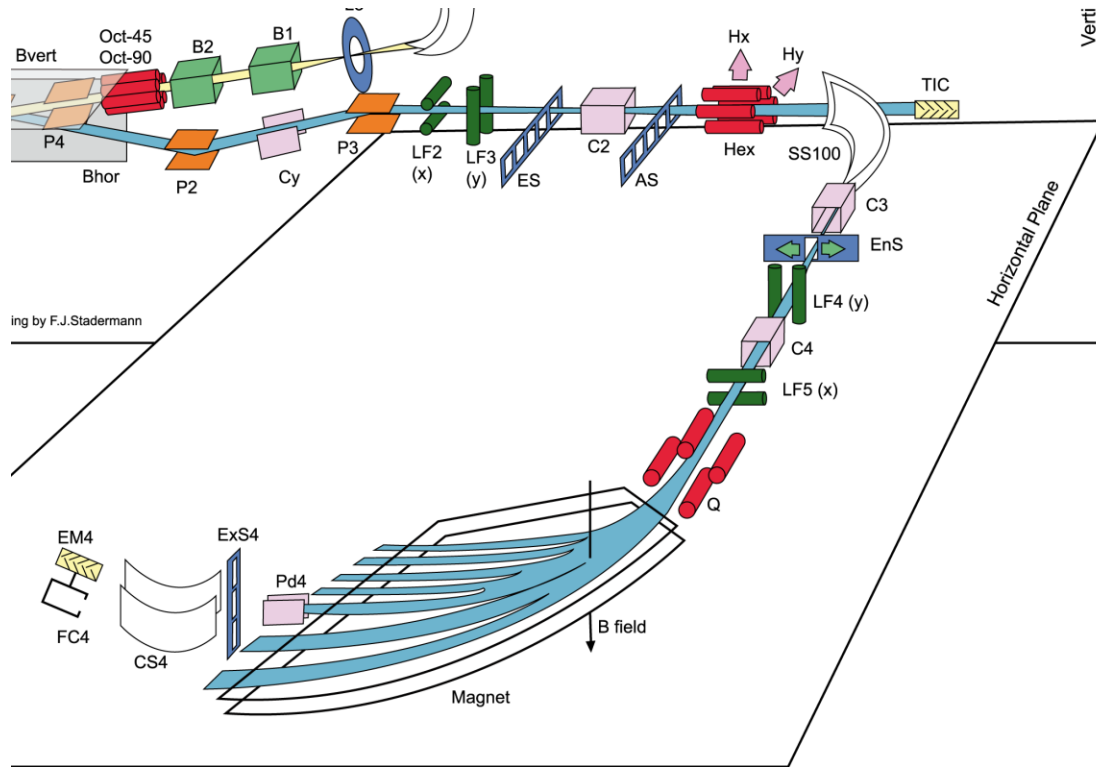
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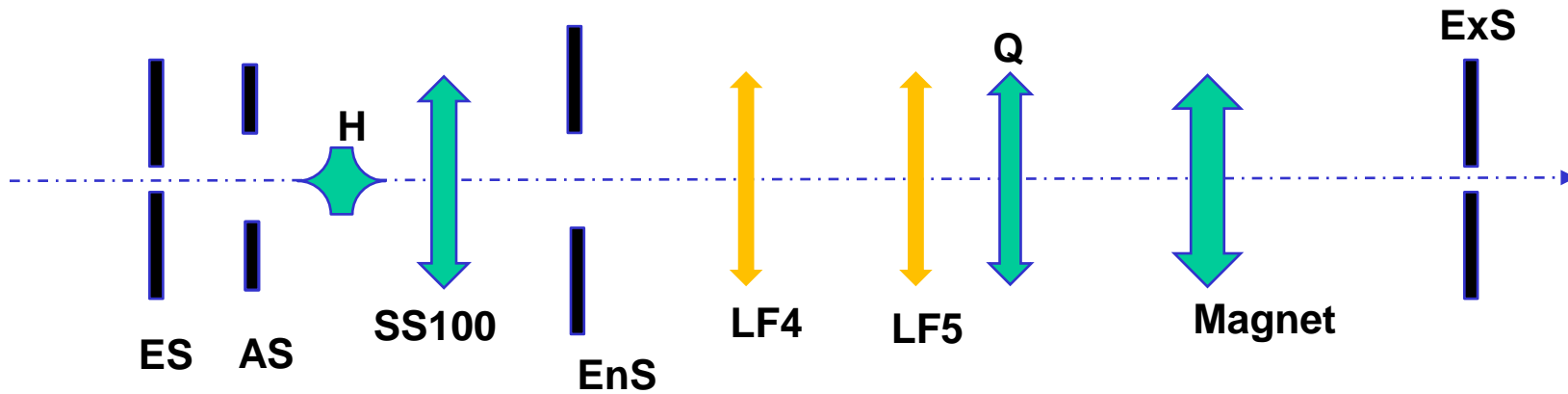
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Mass spectrometer and Mass Resolving Power

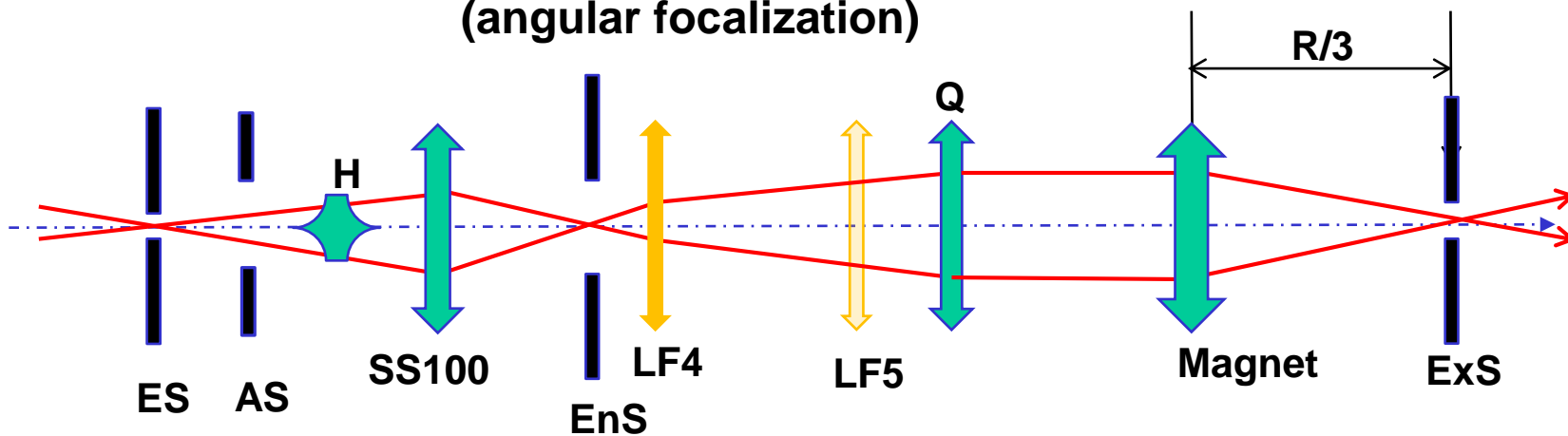


ing by F.J.Stadermann

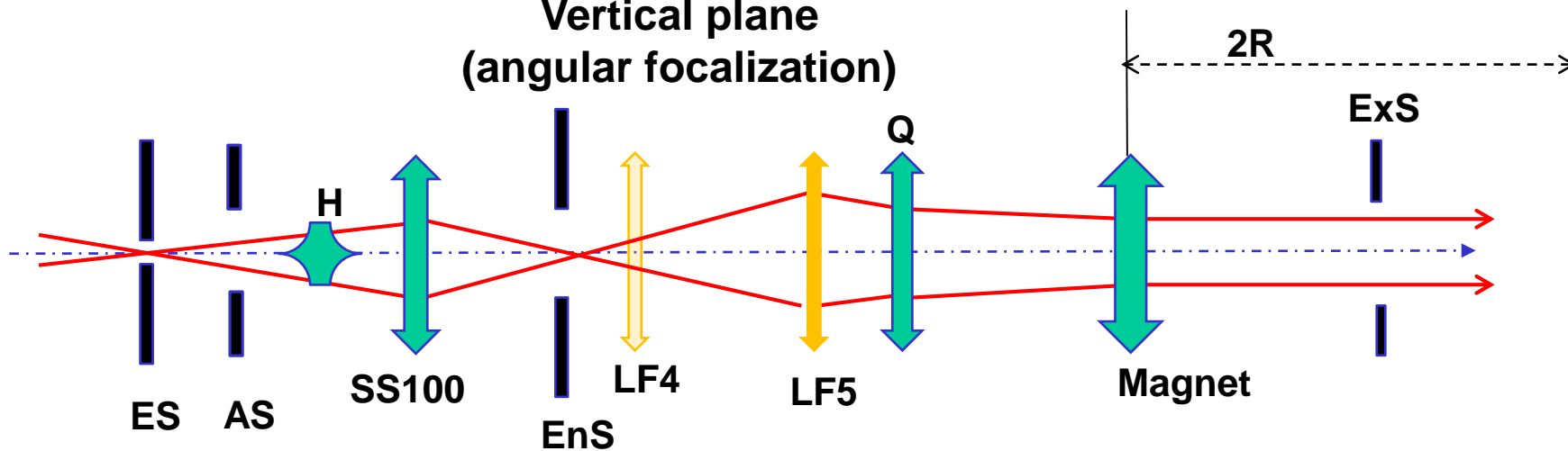


Mass spectrometer and Mass Resolving Power

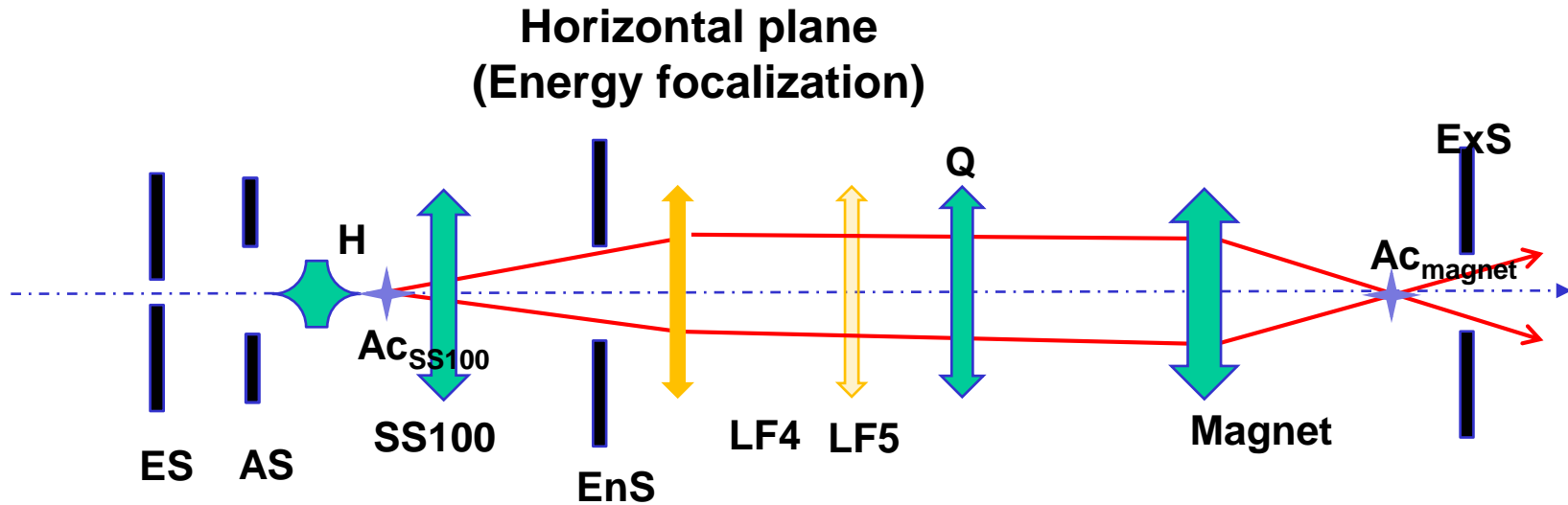
**Horizontal plane
(angular focalization)**



**Vertical plane
(angular focalization)**



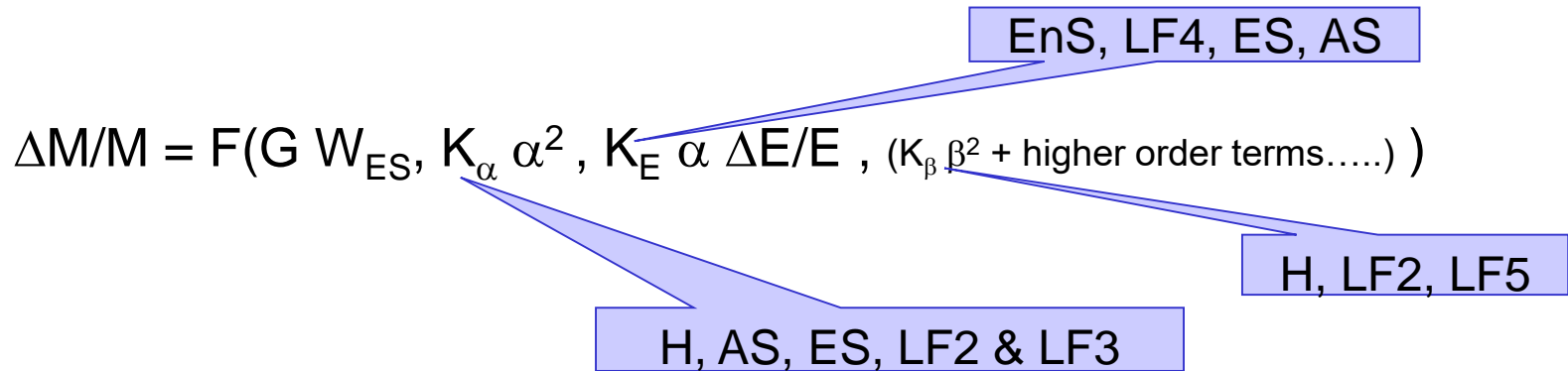
Mass spectrometer and Mass Resolving Power



Two conditions.

- Angular focalization and energy focalization.
- Two lenses Q and LF4.
- Q fulfilled both conditions (angular and energy) at 90%.
- LF4 is in charge of fine energy focusing. Theoretically any LF4 change needs to be compensate by a slight change of Q.

Mass spectrometer and Mass Resolving Power

$$\Delta M/M = F(G W_{ES}, K_a \alpha^2, K_E \alpha \Delta E/E, (K_b \beta^2 + \text{higher order terms.....}))$$


Callouts from the equation:

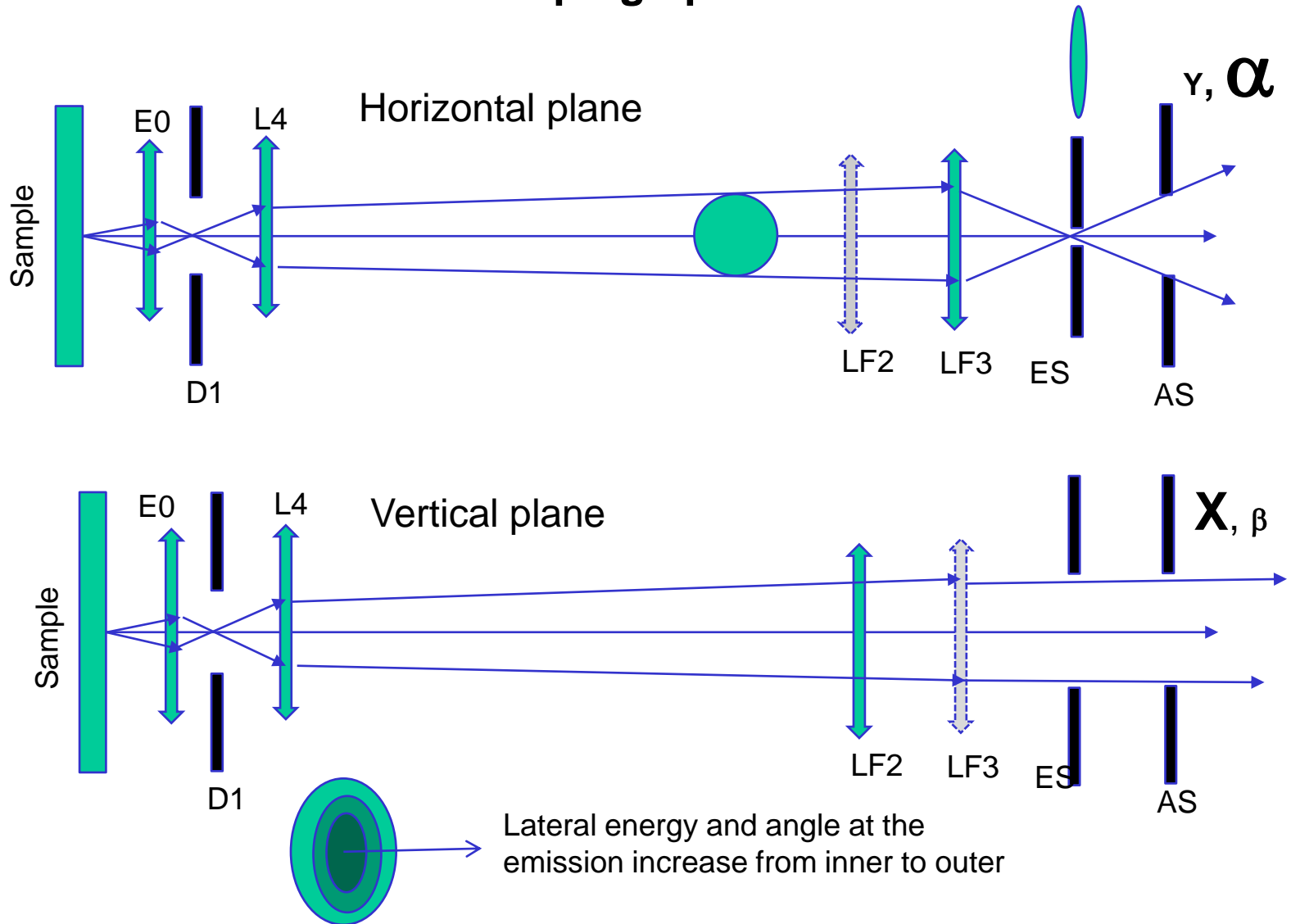
- EnS, LF4, ES, AS (points to $K_b \beta^2$)
- H, LF2, LF5 (points to $K_b \beta^2$)
- H, AS, ES, LF2 & LF3 (points to $K_a \alpha^2$)

- W_{ES} : Entrance slit width (or beam waist)
- G : magnification of the spectrometer. $G = R/537$; as the mass dispersion is $R/2$, MRP is independent of R .
- $K_a \alpha^2$: main second order aperture aberration term,
- $K_E \alpha \Delta E/E$: main chromatic aberration term,

with α and β being the half aperture angle in the radial plane and in the vertical plane and $\Delta E/E$ the relative energy spread of the secondary beam.

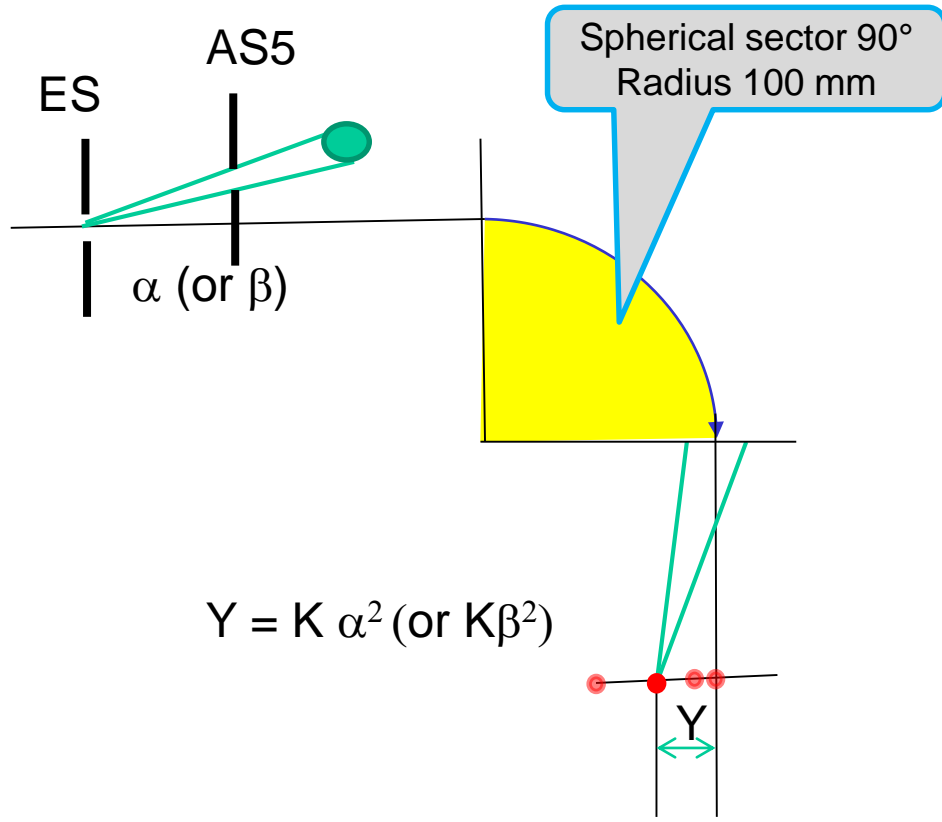
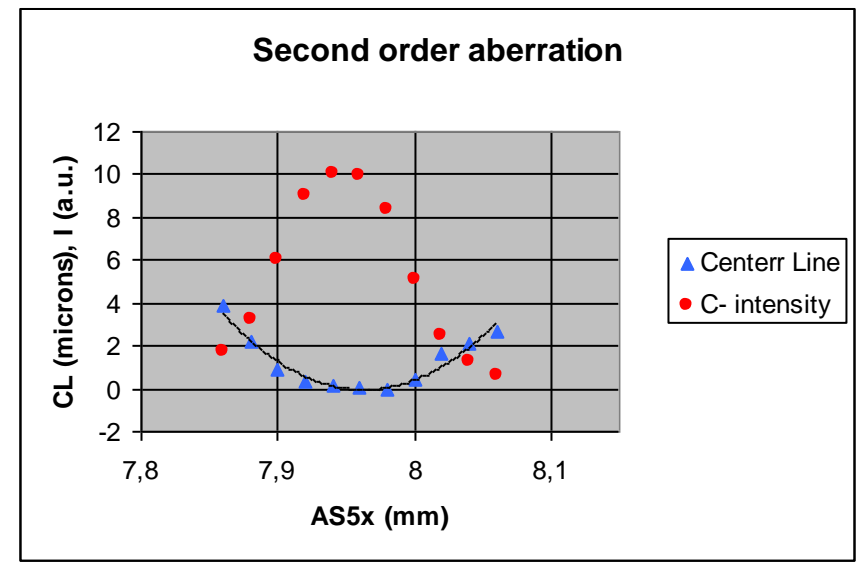
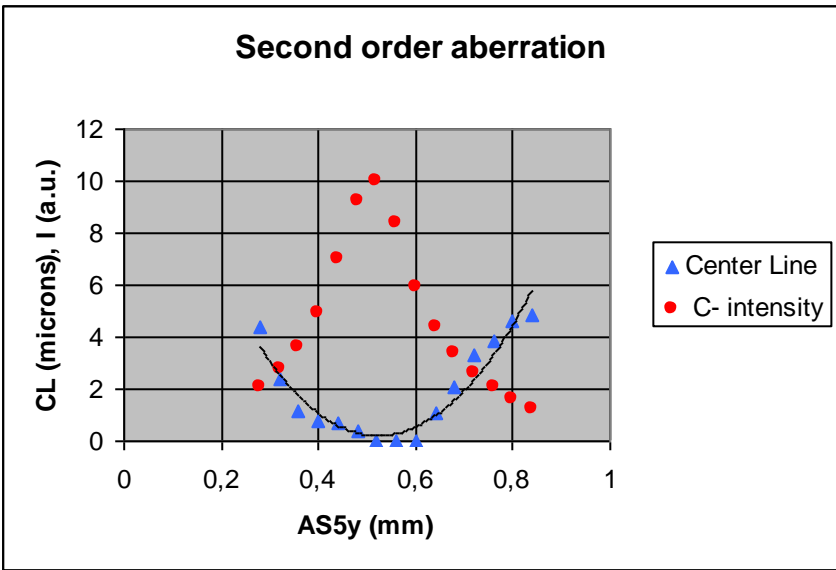
Mass spectrometer and Mass Resolving Power

Shaping optic



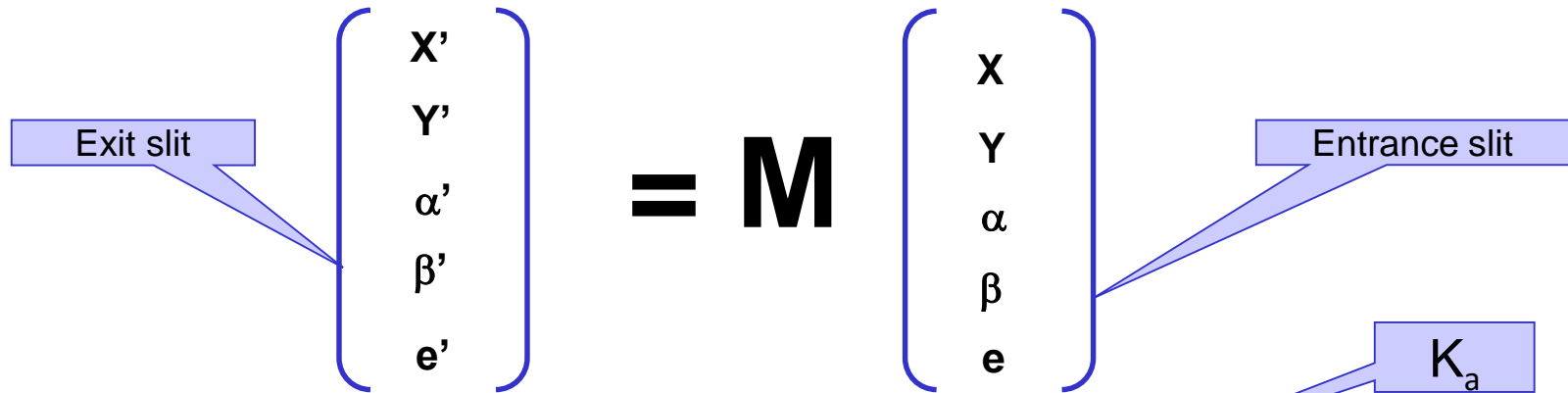
Mass spectrometer and Mass Resolving Power

Second order aperture aberrations



Mass spectrometer and Mass Resolving Power

$$\Delta M/M = F(G W_{ES}, K_{\alpha} \alpha^2, K_E \alpha \Delta E/E, (K_{\beta} \beta^2 + \text{higher order terms.....}))$$



Second order, 30 terms: $x' = \langle xe \rangle x.e + \langle \alpha\alpha \rangle \alpha^2 + \langle \alpha e \rangle \alpha e \dots$

Third order, 70 terms: $x' = \langle xee \rangle x.e^2 + \langle \alpha\beta\beta \rangle \alpha.\beta^2 + \dots$

W_{ES} : Entrance slit width, G : magnification of the spectrometer, K_a, K_b : second order aperture aberration term, K_E chromatic aberration term, with α and β being the half aperture angle in the radial plane and in the vertical plane and $\Delta E/E$ the relative energy spread of the secondary beam.

Mass spectrometer and Mass Resolving Power

Practical rules for MRP tuning:

- Choose ES according to the MRP range and tune Q.

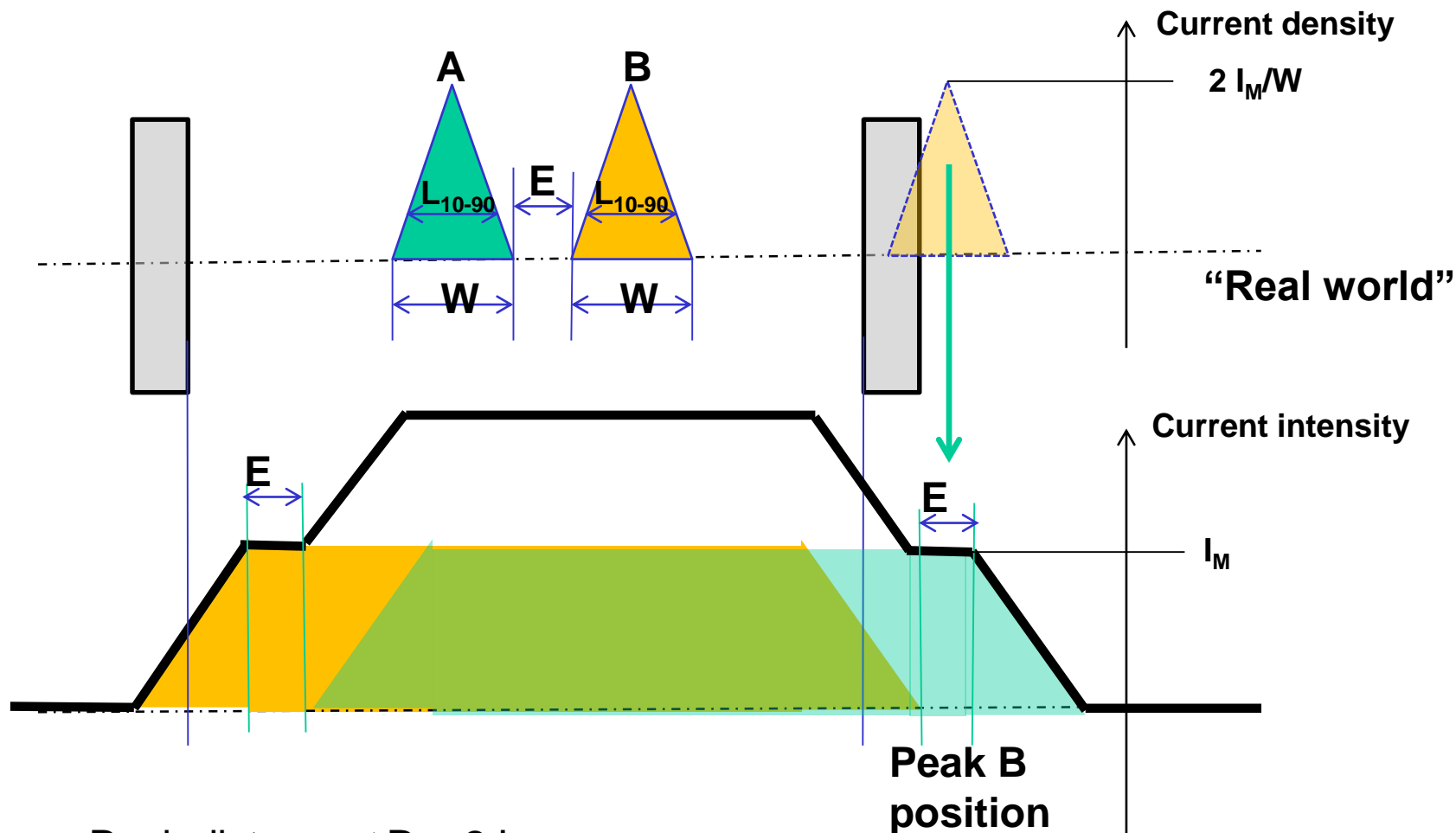
ES #	1	2	3	4	5
MRP	< 4500	< 6000	<8000	<10000	>10000

- Check which kind of aberration are the most dominating (energy or angular):
 - 1) set EnS (-10%), if MRP increases a lot (more than 10-15%) and/or it changes the peak shape, check LF4 (wo EnS).
 - 2) set ASn, if MRP increases a lot (more than 10-15%) and/or it changes the peak shape, check H (X, Y not the value) (wo AS).
- Set ASn and EnS (in this order) to improve MRP and the peak shape.

ES #	1	2	3	4	5
AS#	1 - 2	2-3	2-3	3-4	4-5

- Check C3x (and LF5) to get a C4x scan as flat as possible.

Mass spectrometer and Mass Resolving Power



Peak distance $\Delta R = 2 L_{10-90}$
MRP = $M/DM = R / 2 \Delta R = R / 4 L_{10-90}$
 $E = 0,9 L_{10-90}$ with $L_{10-90} = 0,9 W$

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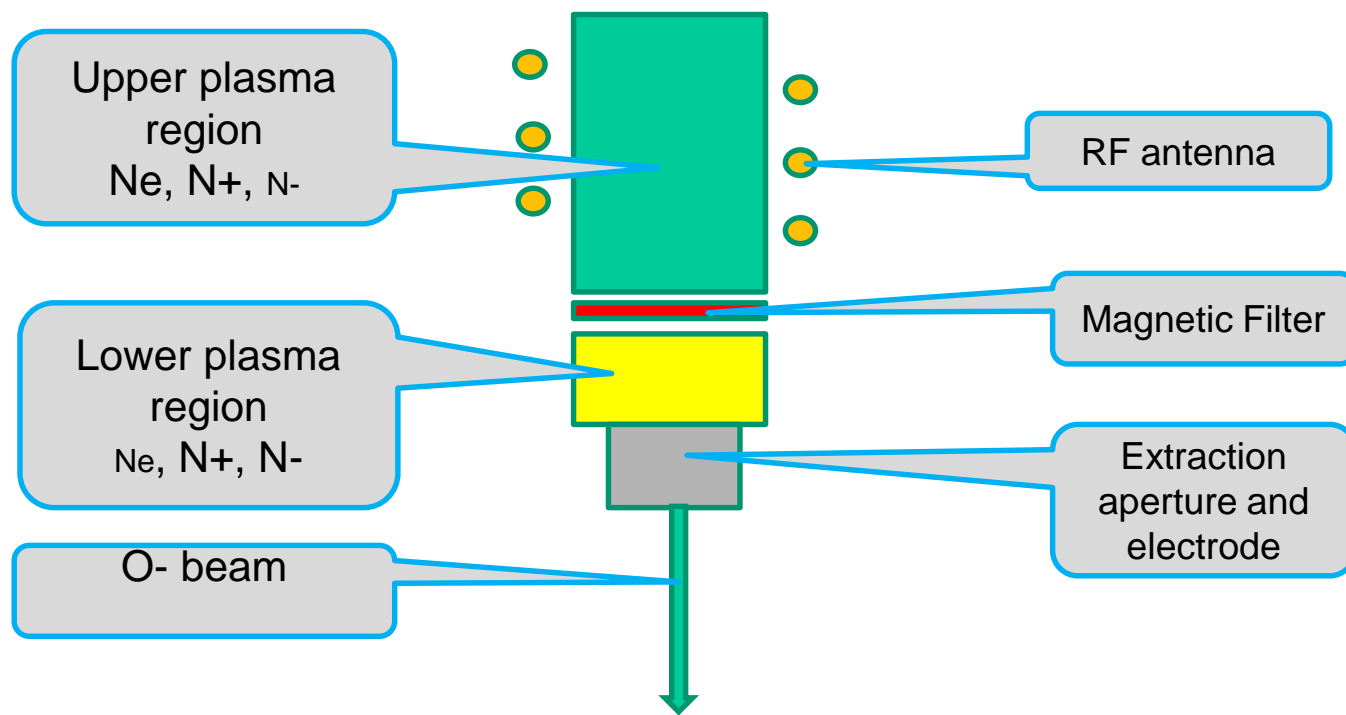
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3/ New O^- ion source

- How it works?
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A new brighter O⁻ RF plasma ion source

Source schematic



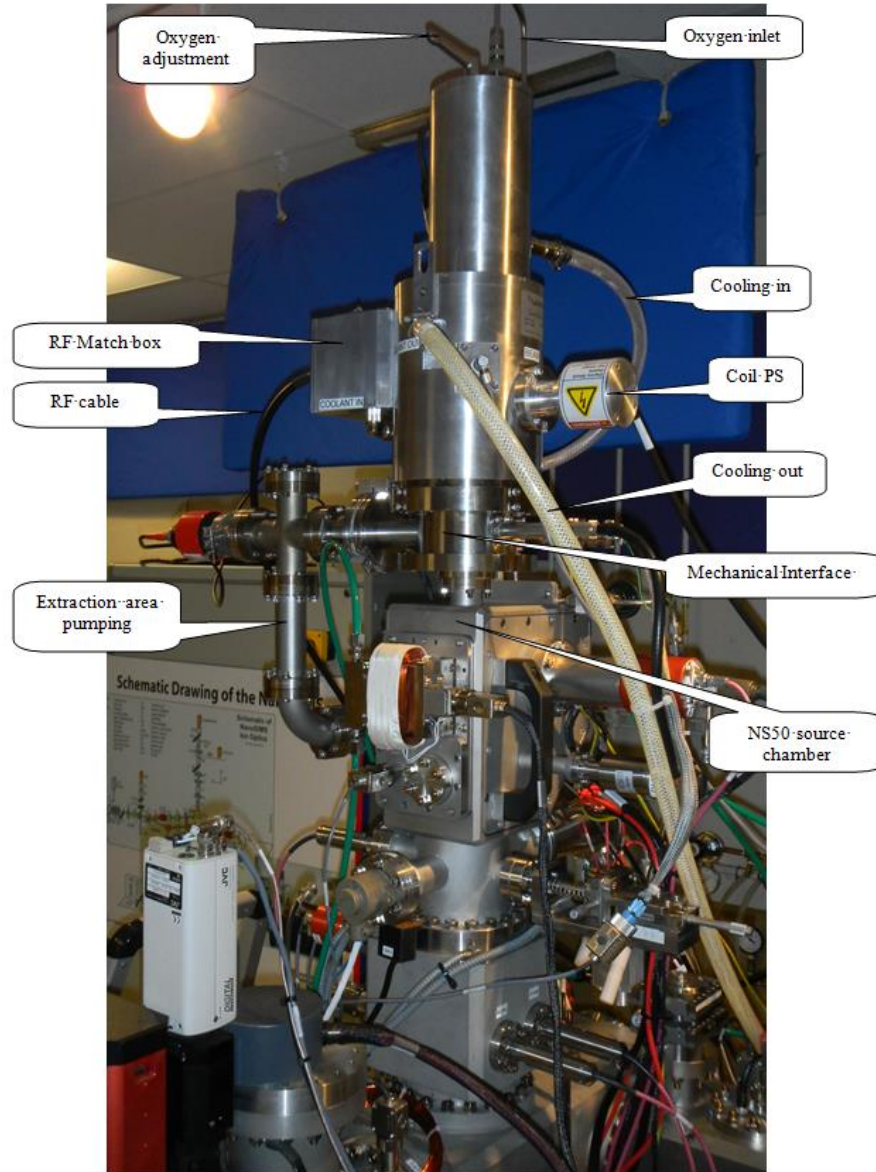
Duoplasmatron

Source diameter: 300 microns
 Brightness: **10-20 mA cm⁻² sr⁻¹**
 Energy dispersion: < 15 eV FWHM

Oregon Physics

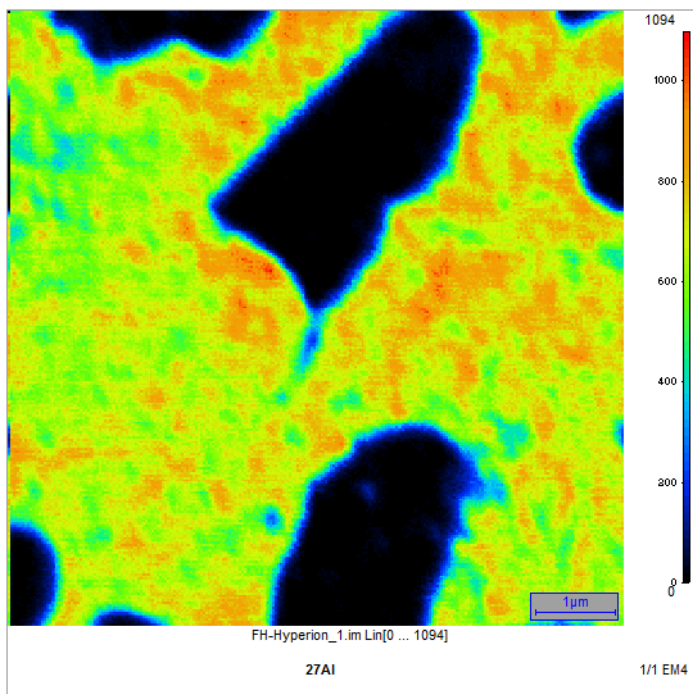
Source diameter: 35-50 microns
 Brightness: **160 mA cm⁻² sr⁻¹**
 Energy dispersion: < 5 eV FWHM

A new brighter O⁻ RF plasma ion source

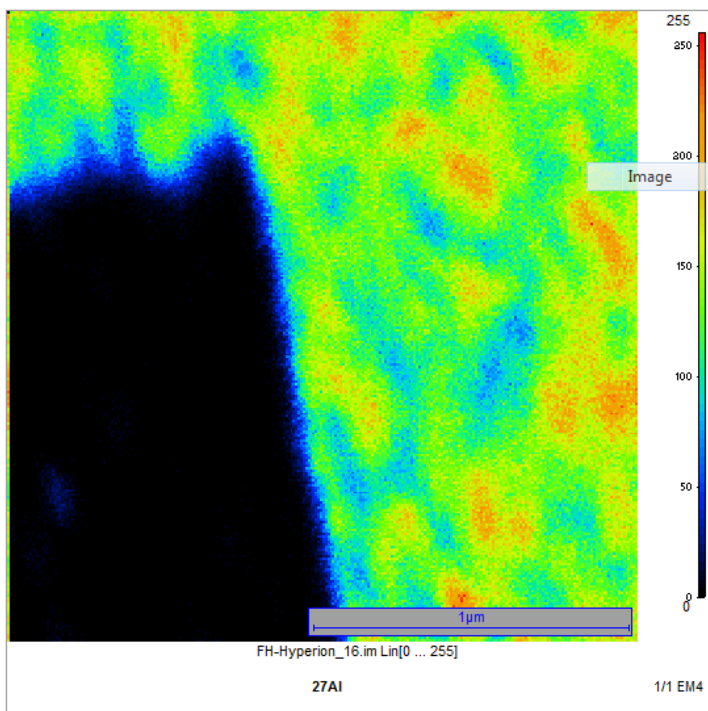


Prototype of the O⁻ source tested on the NanoSIMS of LLNL, CA, USA

O- RF plasma ion source: preliminary tests

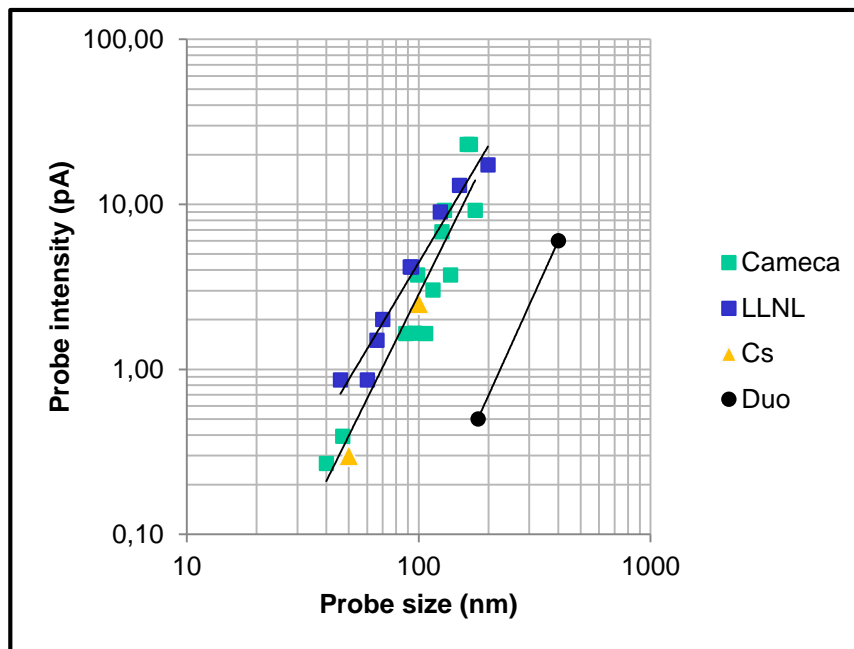


FOV 8 x 8 microns, 200 nm 17.3 pA



FOV 2 x 2 microns, 46 nm 0.86 pA

A new O⁻ RF plasma ion source



Source performances

Source diameter: 70-80 microns

Brightness: **100 mA cm⁻² sr⁻¹**

Energy dispersion: NA

Stability: < 1,6 % over 14h

Lifetime: > 500h on May 20th

